

# IRFPS40N60KPbF

HEXFET® Power MOSFET

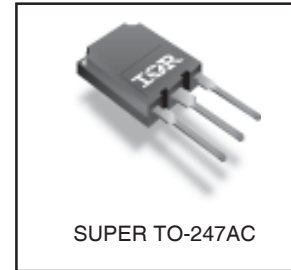
<b>V<sub>DSS</sub></b>	<b>R<sub>DS(on)</sub> typ.</b>	<b>I<sub>D</sub></b>
600V	0.110 Ω	40A

### Applications

- Hard Switching Primary or PFC Switch
- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply
- High Speed Power Switching
- Motor Drive
- Lead-Free

### Benefits

- Low Gate Charge Qg results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dv/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Enhanced Body Diode dv/dt Capability



### Absolute Maximum Ratings

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	40	A
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	24	
I <sub>DM</sub>	Pulsed Drain Current ①	160	
P <sub>D</sub> @ T <sub>C</sub> = 25°C	Power Dissipation	570	W
	Linear Derating Factor	4.5	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	± 30	V
dv/dt	Peak Diode Recovery dv/dt ②	5.5	V/ns
T <sub>J</sub>	Operating Junction and Storage Temperature Range	-55 to + 150	°C
T <sub>STG</sub>			

### Avalanche Characteristics

Symbol	Parameter	Typ.	Max.	Units
E <sub>AS</sub>	Single Pulse Avalanche Energy②	—	600	mJ
I <sub>AR</sub>	Avalanche Current①	—	40	A
E <sub>AR</sub>	Repetitive Avalanche Energy①	—	57	mJ

### Thermal Resistance

Symbol	Parameter	Typ.	Max.	Units
R <sub>θJC</sub>	Junction-to-Case	—	0.22	°C/W
R <sub>θCS</sub>	Case-to-Sink, Flat, Greased Surface	0.24	—	
R <sub>θJA</sub>	Junction-to-Ambient	—	40	

# IRFPS40N60KPbF

International  
IR Rectifier

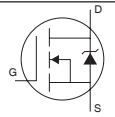
## Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	600	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.63	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$ ⓐ
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	0.110	0.130	$\Omega$	$V_{GS} = 10V, I_D = 24A$ ④
$V_{GS(th)}$	Gate Threshold Voltage	3.0	—	5.0	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
$I_{DSS}$	Drain-to-Source Leakage Current	—	—	50	$\mu A$	$V_{DS} = 600V, V_{GS} = 0V$
		—	—	250		$V_{DS} = 480V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 30V$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS} = -30V$

## Dynamic @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$g_{fs}$	Forward Transconductance	21	—	—	S	$V_{DS} = 50V, I_D = 24A$
$Q_g$	Total Gate Charge	—	—	330	nC	$I_D = 38A$
$Q_{gs}$	Gate-to-Source Charge	—	—	84		$V_{DS} = 480V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge	—	—	150		$V_{GS} = 10V, \text{See Fig. 6 and 13}$ ④
$t_{d(on)}$	Turn-On Delay Time	—	47	—	ns	$V_{DD} = 300V$
$t_r$	Rise Time	—	110	—		$I_D = 38A$
$t_{d(off)}$	Turn-Off Delay Time	—	97	—		$R_G = 4.3\Omega$
$t_f$	Fall Time	—	60	—		$V_{GS} = 10V, \text{See Fig. 10}$ ④
$C_{iss}$	Input Capacitance	—	7970	—	pF	$V_{GS} = 0V$
$C_{oss}$	Output Capacitance	—	750	—		$V_{DS} = 25V$
$C_{riss}$	Reverse Transfer Capacitance	—	75	—		$f = 1.0\text{MHz}, \text{See Fig. 5}$
$C_{oss}$	Output Capacitance	—	9440	—		$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0\text{MHz}$
$C_{oss}$	Output Capacitance	—	200	—		$V_{GS} = 0V, V_{DS} = 480V, f = 1.0\text{MHz}$
$C_{oss \text{ eff.}}$	Effective Output Capacitance	—	260	—		$V_{GS} = 0V, V_{DS} = 0V \text{ to } 480V$ ⑤

## Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	40	A	MOSFET symbol showing the integral reverse p-n junction diode. 
$I_{SM}$	Pulsed Source Current (Body Diode) ①	—	—	160		
$V_{SD}$	Diode Forward Voltage	—	—	1.5	V	$T_J = 25^\circ\text{C}, I_S = 38A, V_{GS} = 0V$ ④
$t_{rr}$	Reverse Recovery Time	—	630	950	ns	$T_J = 25^\circ\text{C}$
		—	730	1090		$T_J = 125^\circ\text{C}$
$Q_{rr}$	Reverse Recovery Charge	—	14	20	$\mu\text{C}$	$T_J = 25^\circ\text{C}$
		—	17	25		$T_J = 125^\circ\text{C}$
$I_{RRM}$	Reverse Recovery Current	—	39	58	A	$T_J = 25^\circ\text{C}$
$t_{on}$	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S+L_D$ )				

### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See Fig. 11)
- ② Starting  $T_J = 25^\circ\text{C}$ ,  $L = 0.84\text{mH}$ ,  $R_G = 25\Omega$ ,  $I_{AS} = 38A$ ,  $dv/dt = 5.5V/ns$  (See Figure 12a)
- ③  $I_{SD} \leq 38A$ ,  $di/dt \leq 150A/\mu s$ ,  $V_{DD} \leq V_{(BR)DSS}$ ,  $T_J \leq 150^\circ\text{C}$
- ④ Pulse width  $\leq 300\mu s$ ; duty cycle  $\leq 2\%$ .
- ⑤  $C_{oss \text{ eff.}}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$

# IRFPS40N60KPbF

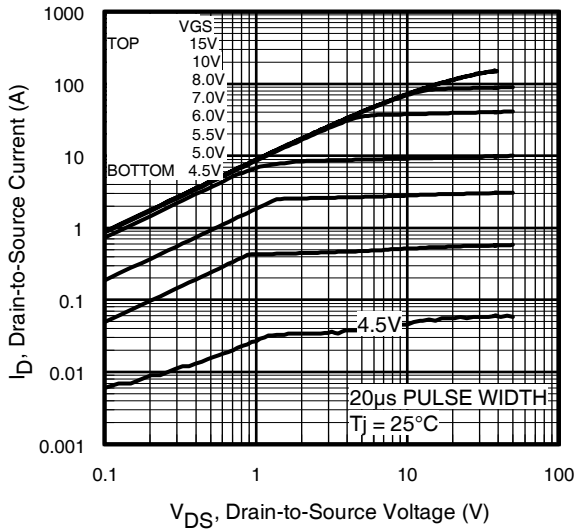


Fig 1. Typical Output Characteristics

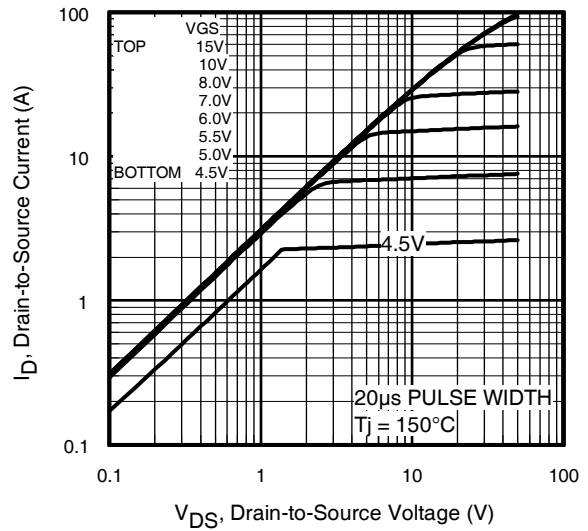


Fig 2. Typical Output Characteristics

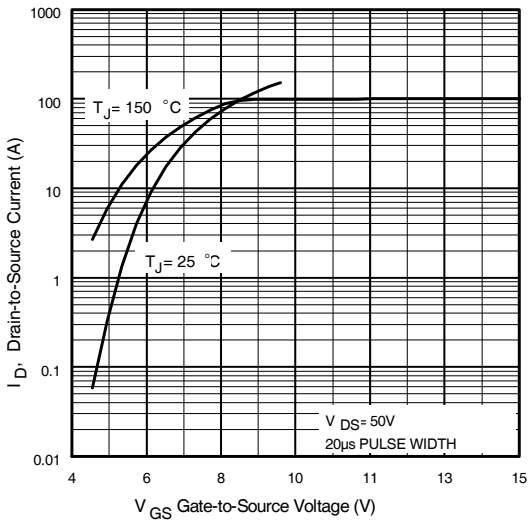


Fig 3. Typical Transfer Characteristics

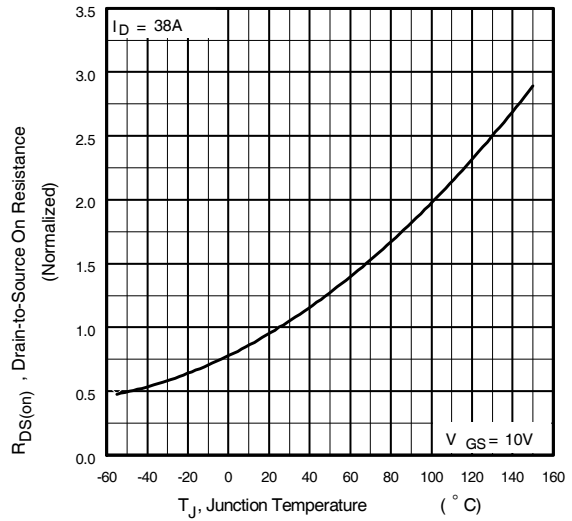
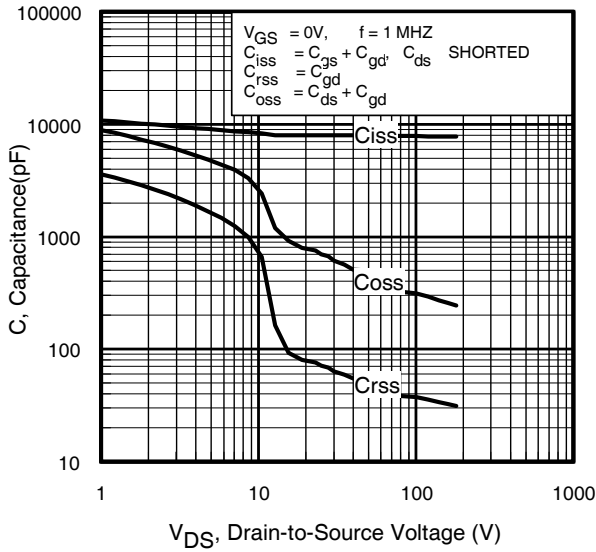


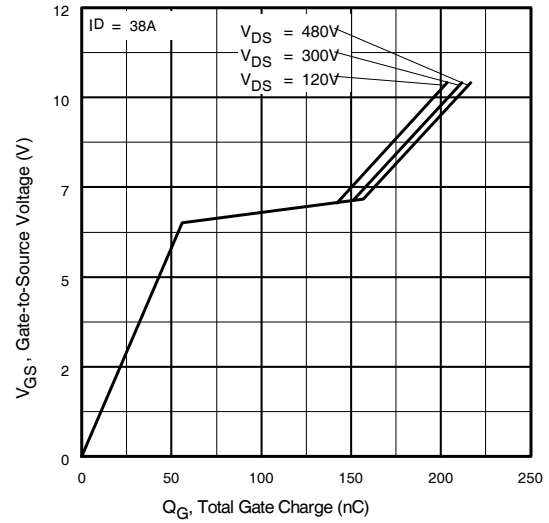
Fig 4. Normalized On-Resistance Vs. Temperature

# IRFPS40N60KPbF

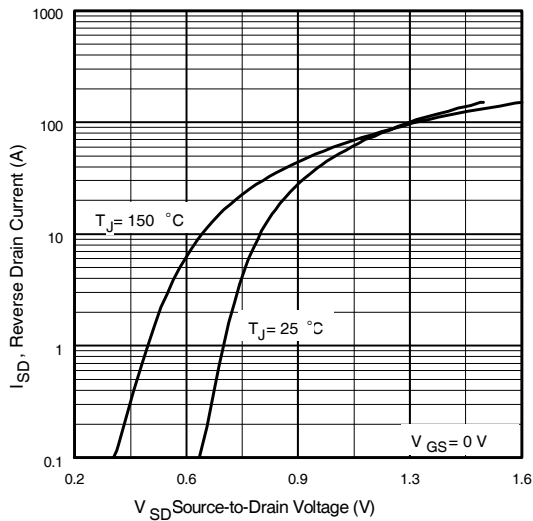
International  
**IR** Rectifier



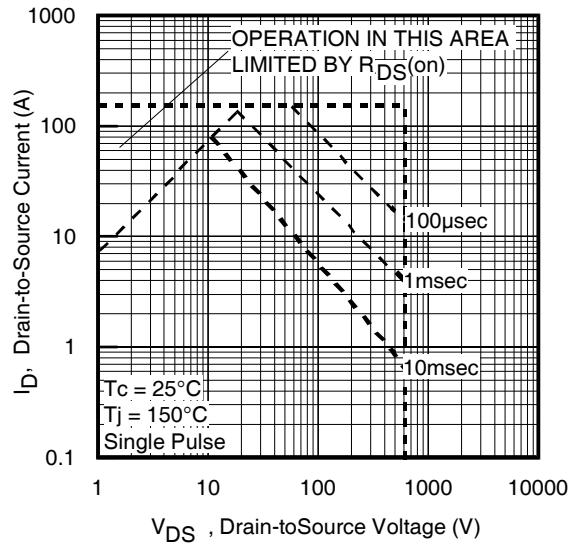
**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



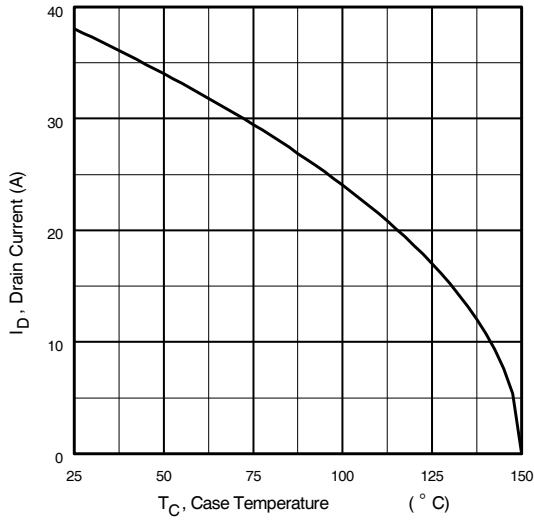
**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



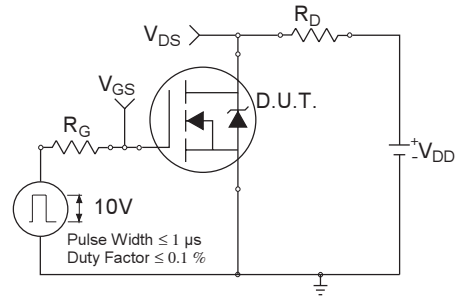
**Fig 7.** Typical Source-Drain Diode Forward Voltage



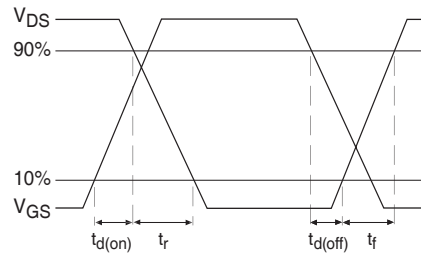
**Fig 8.** Maximum Safe Operating Area



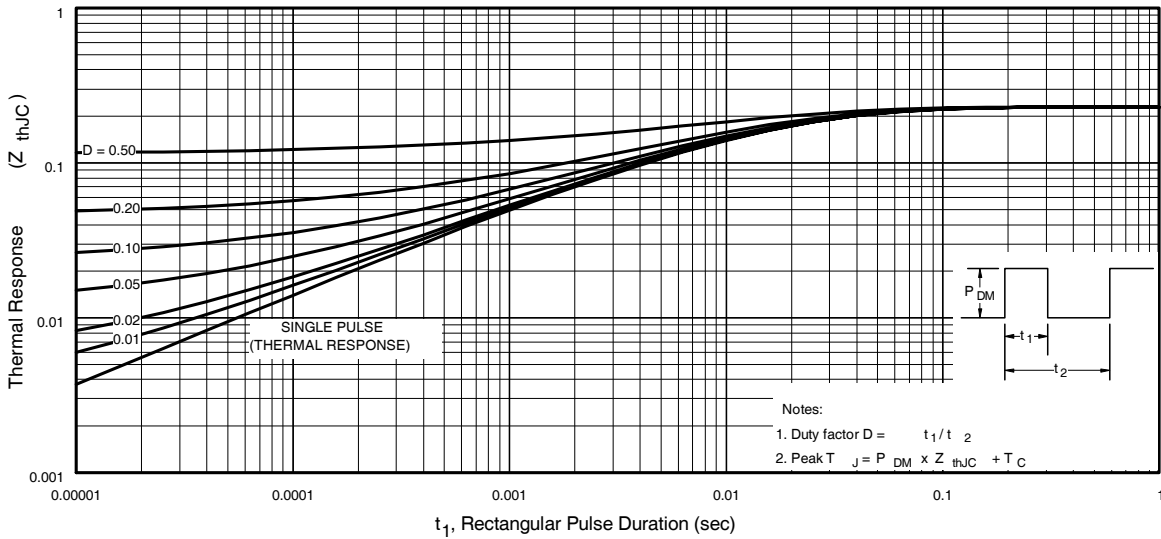
**Fig 9.** Maximum Drain Current Vs. Case Temperature



**Fig 10a.** Switching Time Test Circuit



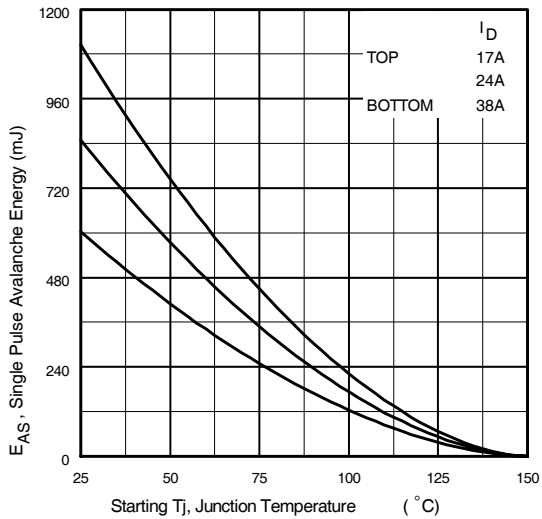
**Fig 10b.** Switching Time Waveforms



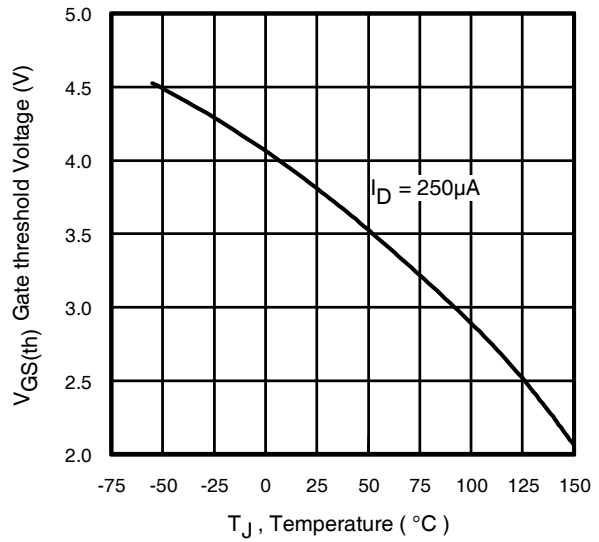
**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case

# IRFPS40N60KPbF

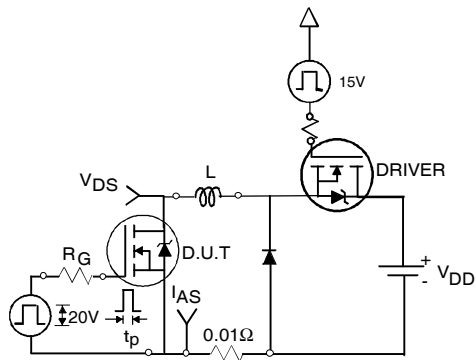
International  
**IR** Rectifier



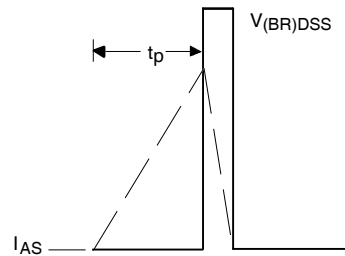
**Fig 12a.** Maximum Avalanche Energy Vs. Drain Current



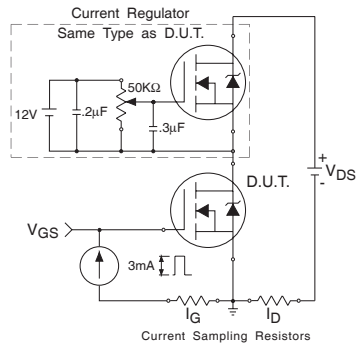
**Fig 14.** Threshold Voltage Vs. Temperature



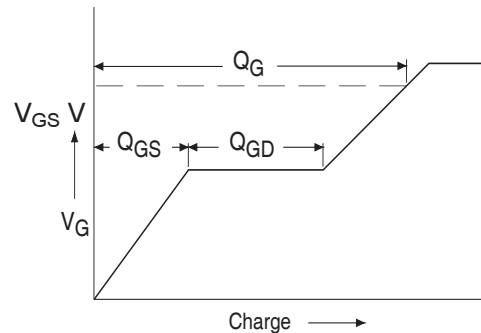
**Fig 12c.** Unclamped Inductive Test Circuit



**Fig 12d.** Unclamped Inductive Waveforms



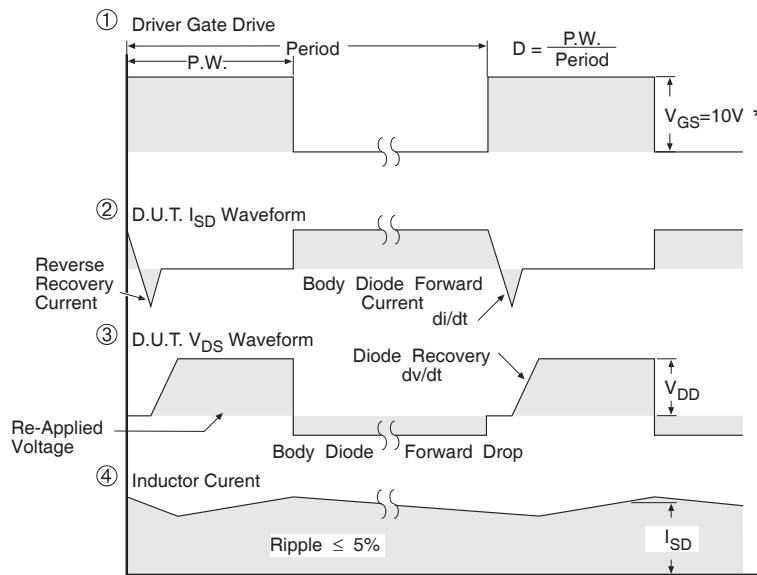
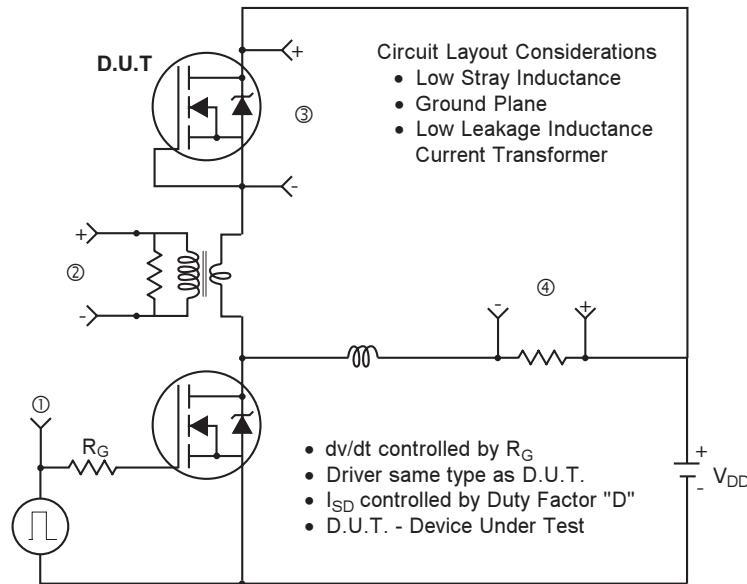
**Fig 13a.** Gate Charge Test Circuit



**Fig 13b.** Basic Gate Charge Waveform

www.irf.com

## Peak Diode Recovery dv/dt Test Circuit



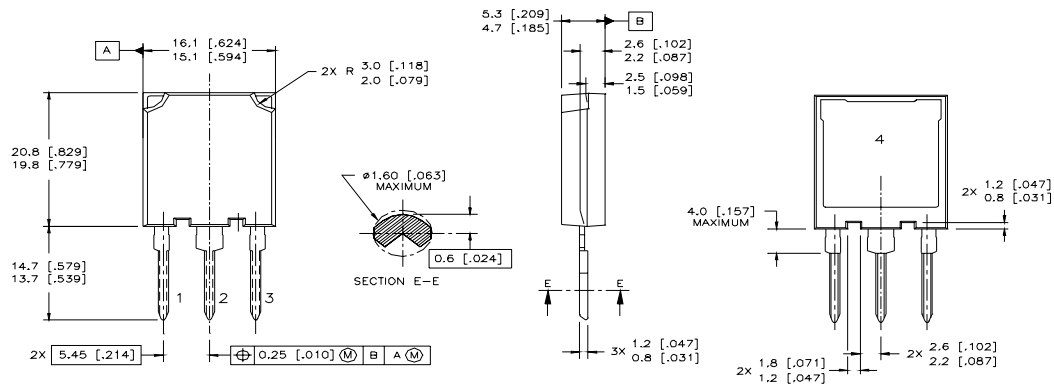
\*  $V_{GS} = 5V$  for Logic Level Devices

**Fig 14.** For N-Channel HEXFET<sup>®</sup> Power MOSFETs

# IRFPS40N60KPbF

International  
**IR** Rectifier

## Case Outline and Dimensions — Super-247



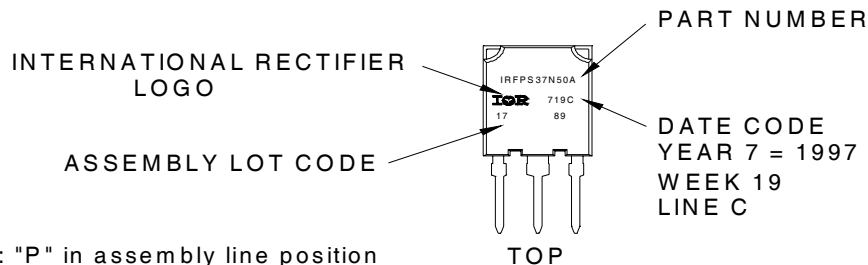
NOTES:  
1. DIMENSIONS & TOLERANCING PER ASME Y14.5M-1994  
2. CONTROLLING DIMENSION: MILLIMETER  
3. DIMENSIONS ARE SHOWN IN MILLIMETRES [INCHES]

LEAD ASSIGNMENTS

MOSFET	IGBT
1 - GATE	1 - GATE
2 - DRAIN	2 - COLLECTOR
3 - SOURCE	3 - EMITTER
4 - DRAIN	4 - COLLECTOR

## Super-247 (TO-274AA) Part Marking Information

EXAMPLE: THIS IS AN IRFPS37N50A WITH  
ASSEMBLY LOT CODE 1789  
ASSEMBLED ON WW 19, 1997  
IN THE ASSEMBLY LINE "C"



Note: "P" in assembly line position indicates "Lead-Free"

Data and specifications subject to change without notice.  
This product has been designed and qualified for the Industrial market.  
Qualification Standards can be found on IR's Web site.

International  
**IR** Rectifier

IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105  
TAC Fax: (310) 252-7903

Visit us at [www.irf.com](http://www.irf.com) for sales contact information.09/04

[www.irf.com](http://www.irf.com)